

IN THE CLAIMS

Please amend the claims as follows:

Claims 1-35 (Canceled).

Claim 36 (Currently Amended) ~~The probe card of claim 35,~~ A probe card
comprising:

a plurality of probes, each probe for contacting with an electrode of a test subject
formed on a substrate to inspect electrical characteristics of the test subject, each probe
including a beam having a leading end portion, an intermediate portion and a base end
portion; the base end portion being a portion for fixing the probe on the probe card; and a
contactor having a substantially trapezoidal shape and disposed at the leading end portion of
the beam, an inner part of the contactor being essentially filled with one or more metals,
wherein the leading end portion is a portion for making a contact with the test subject via the
contactor; and

a probe card main body including first terminals installed on a first surface thereof
and serving as supporting columns for the probes and second terminals installed on a second
surface thereof,

wherein each of the second terminals is electrically connected to a different one of the
first terminals; and the base end portion of each probe is fixed to said different one of the first
terminals,

wherein the probe card main body further includes a stopper, and

wherein the stopper has a body portion substantially identical to the first terminal in
composition and an electrically insulating film formed at least at a stopper surface contacting
a surface of the test subject.

Claim 37 (Canceled)

Claim 38 (Currently Amended) A probe array supporting unit for supporting ~~the a~~ probe array ~~of claim 6~~ with a predetermined tension, wherein the probe array is used in a manufacturing process of a probe card and includes:

a second film-shaped supporting body having elasticity; and

a plurality of probes adhered onto one surface of the second film-shaped supporting body, each probe including a beam and a contactor having a substantially trapezoidal shape, an inner part of the contactor being essentially filled with one or more metals,

wherein the beam has a leading end portion, an intermediate portion and a base end portion, the leading end portion being a portion for making a contact with a test subject via the contactor, the base end portion being a portion for fixing each probe on the probe card; and the contactor is disposed at the leading end portion of the beam, a top portion of the contactor being embedded in the second film-shaped supporting body,

the probe array supporting unit comprising:

a first fixing part, which is a first frame shaped structure;

a second fixing part, wherein the second fixing part is a second frame shaped structure and overlapped with the first fixing part via the probe array ~~of claim 6~~,

wherein while the second fixing part is overlapped with the first fixing part, the probe array is supported by both fixing parts under a predetermined tension; and

a locking part for locking and fixing the overlapped first and second fixing parts.

Claim 39 (Previously Presented): A probe array supporting unit of claim 38, wherein the first fixing part has a first lower surface and a first upper surface and the first upper surface is a first slant surface declining from an outer circumference to an inner circumference of the first frame shaped structure; and

the second fixing part is piled on the first fixing part and has a second lower surface and a second upper surface, and the second lower surface is a second slant surface declining from an outer circumference to an inner circumference of the second frame shaped structure and having a substantially same slant angle as that of the first slant surface.